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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/743,583	12/22/2003	Steven Allen Carlson	1141.011	7979
7590 06/09/2005			EXAMINER	
Attn: Intellectual Property Department			TRA, TUYEN Q	
Optodot Corporation Suite 305			ART UNIT	PAPER NUMBER
214 Lincoln St.			2873	
Allston, MA 02134			DATE MAILED: 06/09/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
Office Action Commons	10/743,583	CARLSON, STEVEN ALLEN				
Office Action Summary	Examiner	Art Unit				
	Tuyen Q. Tra	2873				
The MAILING DATE of this communication ap Period for Reply	pears on the cover sheet w	rith the correspondence address				
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a rep. If NO period for reply is specified above, the maximum statutory period. - Failure to reply within the set or extended period for reply will, by statut Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, however, may a ply within the statutory minimum of thi I will apply and will expire SIX (6) MOI le, cause the application to become A	reply be timely filed rty (30) days will be considered timely. NTHS from the mailing date of this communication. BANDONED (35 U.S.C. § 133).				
Status		•				
1)⊠ Responsive to communication(s) filed on 04 A	April 2005.					
2a) ☐ This action is FINAL . 2b) ☑ Thi	<u> </u>					
·	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims						
4) ⊠ Claim(s) <u>1-40,42-44 and 49-66</u> is/are pending 4a) Of the above claim(s) is/are withdra 5) ⊠ Claim(s) <u>29-40,42-44 and 49-54</u> is/are allowe 6) ⊠ Claim(s) <u>1-3,6-26,55-58 and 61-66</u> is/are reje 7) ⊠ Claim(s) <u>4,5,27,28,59 and 60</u> is/are objected 8) □ Claim(s) are subject to restriction and/	awn from consideration. d. cted. to.					
Application Papers						
9) The specification is objected to by the Examin 10) The drawing(s) filed on 22 December 2003 is/ Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the E	are: a)⊠ accepted or b)[e drawing(s) be held in abeya ction is required if the drawing	nce. See 37 CFR 1.85(a). g(s) is objected to. See 37 CFR 1.121(d).				
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreig a) All b) Some * c) None of: 1. Certified copies of the priority document of the priority document of the priority document of the certified copies o	nts have been received. Its have been received in a corrective ority documents have been au (PCT Rule 17.2(a)).	Application No n received in this National Stage				
Attachment(s)						
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)		Summary (PTO-413) (s)/Mail Date				
Notice of Draftsperson's Patent Drawing Review (P10-946) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date		Informal Patent Application (PTO-152)				

DETAILED ACTION

Applicant's arguments with respect to claims 1-26 have been considered but are moot in view of the new ground of rejection.

Claim Rejections - 35 USC § 112

1. The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

A broad range or limitation together with a narrow range or limitation that falls within the broad range or limitation (in the same claim) is considered indefinite, since the resulting claim does not clearly set forth the metes and bounds of the patent protection desired. Note the explanation given by the Board of Patent Appeals and Interferences in Ex parte Wu, 10 USPQ2d 2031, 2033 (Bd. Pat. App. & Inter. 1989), as to where broad language is followed by "such as" and then narrow language. The Board stated that this can render a claim indefinite by raising a question or doubt as to whether the feature introduced by such language is (a) merely exemplary of the remainder of the claim, and therefore not required, or (b) a required feature of the claims. Note also, for example, the decisions of Ex parte Steigewald, 131 USPQ 74 (Bd. App. 1961); Ex parte Hall, 83 USPQ 38 (Bd. App. 1948); and Ex parte Hasche, 86 USPQ 481 (Bd. App. 1949). In the present instance, claims 2, 16-18 and 57 recites the broad recitation "infrared region from 700nm-1700nm", "700nm-2000nm", "2000nm-3000nm" and "above 3000nm", and the claims also recites in independent claims "1250nm-1700nm" which is the narrower statement of the range/limitation.

Application/Control Number: 10/743,583 Page 3

Art Unit: 2873

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 3. Claims 1, 2, 56, 57, 65 and 66 are rejected under 35 U.S.C. 102(b) as being anticipated by Mihara et al. (U.S. Pat. 5,482,822 A).

Mihara et al. discloses an infrared-absorptive compound and optical recording medium making use of the same comprising of an infrared reflective layer comprises an organic radical cation compound, which redical cation compound exhibits a reflectance in the infrared region from 1250 nm to 1700 nm (col. 136, lines 43-45).

Claim Rejections - 35 USC § 103

- 4. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which the subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 5. Claims 3, 6-8, 55, 58 and 61-64 are rejected under 35 U.S.C. 103(a) as being unpatentable over Mihara et al. (U.S. Pat. 5,482,822 A), as applied to claim 1 above, in view of Kitayama et al. (US Patent 6,475,590).
- a) With respect to claims 3 and 58, Mihara et al. discloses an infrared-absorptive compound and optical recording medium making use of the same comprising of an infrared reflective layer comprises an organic radical cation compound, which redical

Application/Control Number: 10/743,583

Art Unit: 2873

cation compound exhibits a reflectance in the infrared region from 1250 nm to 1700 nm (col. 136, lines 43-45).

However, Mihara et al. does not disclose radical cation is a salt of an aminium radical cation. Within the same field invention, Kitayama et al. teach of an aminium salt compound with teaching of aminium salt used in radical cation compound.

It would have been obvious, therefore, at the time the invention was made to a person having skill in the art to construct the optical device with radical cation compound such as disclosed by Mihara et al., with aminium salt compound with teaching of aminium salt used in radical cation compound such as discloses by Kitayama et al., for purpose of recording optical medium.

- b) With respect to claims 6-8 and 61-63, Kitayama et al. further discloses wherein the thickness of the reflective layer is 0.1 to 0.3 microns; wherein the thickness of the reflective layer is 0.2 to 8 microns; wherein the thickness of the reflective layer is 0.4 to 1 micron (col. 9, lines 50-53).
- c) With respect to claims 55 and 64, Kitayama et al. further discloses wherein the infrared reflective layer comprises from about 70 percent to 100 percent by weight of said organic radical cation compound and from 0 percent to about 30% by weight of an organic polymer.
- 6. Claims 9-26 are rejected under 35 U.S.C. 102(b) as being anticipated by Oguchi et al. (U.S. Pat. 4,921,780A) in view of Mihara et al. (U.S. Pat. 5,482,822 A).
- a) With respect to claim 9, Oguchi et al. discloses an optical recording medium and method thereof in Figures 1, 2, 3, 4 comprising of a reflective layer (organic thin film

Application/Control Number: 10/743,583

Art Unit: 2873

which have high reflectance) that is applied over a substrate (item 1), wherein the reflective layer (item 2) comprises a reflective organic free radical compound (i.e. comprising of hexafluoroarsenate in col. 4, line 61) (col.1, lines 62-66).

However, Oguchi et al. does not teach infrared region of 1250nm-1700nm. With the same field of endeavor, Mihara et al. discloses an infrared-absorptive compound and optical recording medium making use of the same with teaching of redical cation compound exhibits a reflectance in the infrared region from 1250 nm to 1700 nm (col. 136, lines 43-45).

It would have been obvious, therefore, at the time the invention was made to a person having skill in the art to construct the optical device with radical cation compound such as disclosed by Oguchi et al., with redical cation compound exhibits a reflectance in the infrared region from 1250 nm to 1700 nm such as discloses by Mihara et al., for purpose of obtaining large absorbing infrared region.

- b) With respect to claim 10, Oguchi et al. further discloses wherein the reflective layer is visibly transparent.
- c) With respect to claims 11-18, Oguchi et al. further discloses wherein the reflective layer is opaque to optically reading the substrate at one or more infrared wavelengths; wherein the reflective layer is reflective at the one or more infrared wavelengths; wherein the reflective layer has greater than 10% reflectance at the one or more infrared wavelengths; wherein the reflective layer has greater than 20% reflectance at the one or more infrared wavelengths; wherein the reflective layer has greater than 30% reflectance at the one or more infrared wavelengths; wherein the one

Application/Control Number: 10/743,583 Page 6

Art Unit: 2873

or more infrared wavelengths are in the infrared region of 700 to 2000 nm; wherein the one or more infrared wavelengths are in the infrared region of 2000 to 3000 nm; wherein the one or more infrared wavelengths are in the infrared region at wavelengths greater than 3000 nm.

- d) With respect to claims 19-24, Oguchi et al. further discloses wherein the reflective layer is opaque to optically reading the substrate at one or more visible wavelengths; wherein the reflective layer is reflective at the one or more visible wavelengths; wherein the reflective layer has greater than 10% reflectance at the one or more visible wavelengths; wherein the reflective layer has greater than 20% reflectance at the one or more visible wavelengths; wherein the reflective layer has greater than 30% reflectance at the one or more visible wavelengths; wherein the one or more visible wavelengths; wherein the one or more visible wavelengths are in the visible region of 580 to 700 nm.
- e) With respect to claims 25-26, Oguchi et al. further discloses wherein the organic free radical compound is a salt of an organic radical cation; wherein the organic free radical compound is a salt of an aminium radical cation.

Allowable Subject Matter

7. Claims 29-40, 42-44 and 49-54 are allowed.

The reason for the indication of allowable subject matter is that (claim 29) a marking system comprising a reflective layer that is applied over a substrate, wherein the reflective layer comprises a reflective organic free radical compound; and wherein an image layer is applied in an imagewise pattern overlying the reflective layer, wherein the image layer comprises optically readable information; (claim 44) wherein

an image layer applied in an imagewise pattern overlying the at least one of the one or more reflective layers, the image layer comprising optically readable information, is optically readable at the one or more infrared wavelengths when scanned from the side of the card stock on which the image layer was applied and is not optically readable at the one or more infrared wavelengths when scanned from the side of the card stock opposite from which the image layer was applied; (claim 49) wherein the method comprises a step (iii) of applying an image layer in an imagewise pattern over the reflective layer, wherein the image layer comprises optically readable information disclosed in the claims is not found in the prior art.

8. Claims 4, 5, 27, 28, 59 and 60 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

The reason for the indication of allowable subject matter is that (claim 4, 28, 59) wherein the organic radical cation compound is a salt of a tetrakis(phenyl)-1,4-bezenediamine radical cation; (claims 5, 28, 60) wherein said organic radical cation compound is a salt of a tris(phenyl)-1,4-benzenediamine radical cation disclosed in the claims is not found in the prior art.

Conclusion

9. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tuyen Tra whose telephone number is (571) 272-2343. The examiner can normally be reached on Monday to Thursday from 8:30am to 6:00pm.

Art Unit: 2873

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Georgia Epps, can be reached on (571) 272 - 2328. The fax number for this Group is (703) 872-9306.

tt

May 31, 2005

Hung Xuan Dang

Primary Examiner